


<b>Search Notes</b>  	<b>Application/Control No.</b>  10526161	<b>Applicant(s)/Patent Under Reexamination</b>  GIEHRL ET AL.
	<b>Examiner</b>  THOMAS H STEVENS	<b>Art Unit</b>  2121

SEARCHED			
Class	Subclass	Date	Examiner
700	83	4/1/08	THS
700	83	10/16/08	ths
703	13,14	1/15/2010	ths
716	1,4	1/15/2010	ths
700	83	2/13/2010	ths
703	13,14	2/13/2010	ths
716	1,4	2/13/2010	ths

SEARCH NOTES		
Search Notes	Date	Examiner
EAST: see search report	4/1/08	THS
Google/Google Scholar: see search report	4/1/08	THS
EAST: see search report	4/16/08	THS
Google/Google Scholar: see search report	4/16/08	THS
ACM: see search report	4/16/08	THS
INSPEC: see search report	4/16/08	THS
EAST: see search report	4/17/08	THS
Google Scholar: see search report	4/17/08	THS
EAST: see search report	10/16/08	THS
EAST: see search report	1/21/09	THS
EAST: see search report	1/23/09	THS
received EIC search from G. St. Leger	1/13/2010	THS
EAST:see search report	1/15/2010	THS
EAST: see search report	2/13/2010	THS

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
703	13,14	2/13/2010	THS
716	1,4	2/13/2010	THS
700	83	2/13/2010	THS

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